

Silicon Carbide PiN Diode Chip

Features

- 10 kV blocking
- 250 °C operating temperature
- Fast turn off characteristics
- Soft reverse recovery characteristics
- Ultra-Fast high temperature switching

Advantages

- Industry's lowest conduction losses
- Reduced stacking
- · Reduced system complexity/Increased reliability



Applications

- Voltage Multiplier
- Ignition/Trigger Circuits
- Oil/Downhole
- Lighting
- Defense

Maximum Ratings at T_j = 250 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
Repetitive peak reverse voltage	V _{RRM}		10	kV
Continuous forward current	I _F	T _C ≤ 150 °C	2	А
RMS forward current	I _{F(RMS)}	T _C ≤ 150 °C	1	А
Operating and storage temperature	T _j , T _{stg}		-55 to 250	°C

Electrical Characteristics at T_j = 250 °C, unless otherwise specified

Parameter	Symbol	Conditions -		Values		11	
				min.	typ.	max.	Unit
Diode forward voltage	V _F	I _F = 2 A, T _j = 2	25 °C		4.4	4.8	V
		I _F = 2 A, T _j = 225 °C			4.1	4.5	v
Reverse current	I _R	V _R = 10 kV, T _j =	= 25 °C		0.1	3	
		V _R = 10 kV, T _j =	225 °C			50 ^{µA}	μA
Total reverse recovery charge	Q _{rr}	I _E ≤ I _{E.MAX}	V _R = 1000 V		558		nC
	~II	$dI_{\rm F}/dt = 70 \text{A/\mu s}$	I _F = 1.5 A				
Switching time	ts	T _j = 225 °C	V _R = 1000 V I _F = 1.5 A		< 236		ns
Total capacitance	С	V _R = 1 V, f = 1 MHz	, T _i = 25 °C		20		
		V _R = 400 V, f = 1 MH	z, T _i = 25 °C		5		pF
		V _R = 1000 V, f = 1 MH	lz, Τ _j = 25 °C		4		
Total capacitive charge	Q _c	V _R = 1000 V, f = 1 MH	lz, T _j = 25 °C		5.34		nC

*For chip size and metallization, please refer to the mechanical datasheet (must have a non-disclosure agreement with GeneSiC Semiconductor).

Electrical Datasheet*

GA01PNS100-CAL

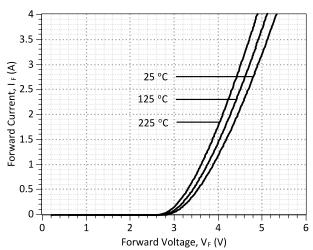


Figure 1: Typical Forward Characteristics

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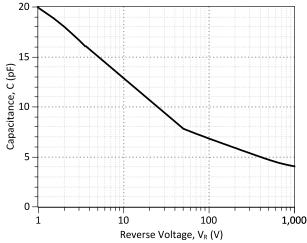
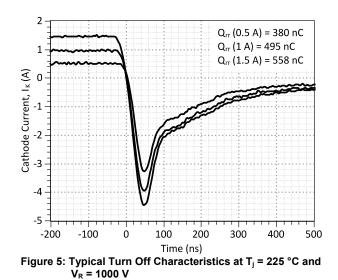


Figure 3: Typical Junction Capacitance vs Reverse Voltage Characteristics



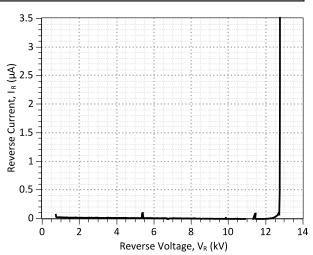


Figure 2: Typical Reverse Characteristics

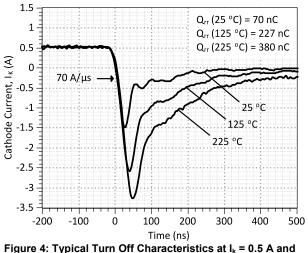


Figure 4: Typical Turn Off Characteristics at $I_k = 0.5$ A and $V_R = 1000$ V

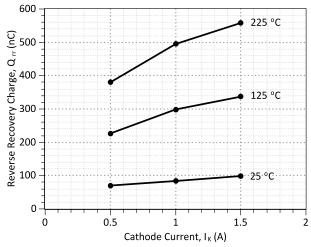


Figure 6: Reverse Recovery Charge vs Cathode Current

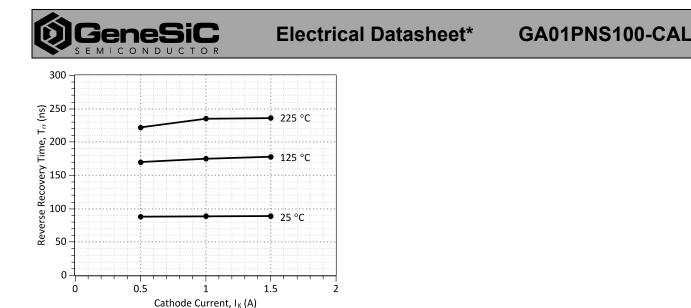


Figure 7: Reverse Recovery Time vs Cathode Current

Revision History							
Date	Revision	Comments	Supersedes				
2012/08/15	0	Initial release					

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